PCN I	Number:	20150122001				PCN Da	ite:	02/12/2015		
Title:	Title: Qualification of ASESH for Alternate Assembly/Test and new material set for select MSOP Devices									
Custo	Customer Contact: PCN Manager Dept: Quality Services									
<b>Proposed 1<sup>st</sup> Ship Date:</b> 05/12/2015 <b>Estimated Sample Availability:</b> 04/12/2015										
Change Type:										
$\boxtimes$ A	Assembly Site		☐ Assembly Process ☐ Assembly Materials				ls			
	Design		Electrical S	Spe	ecificat	ion		Mechanical S	Specif	ication
$\boxtimes$ T	est Site		Packing/SI	hip	ping/L	abeling		Test Process	;	
V	Vafer Bump Site		Wafer Bun	Wafer Bump Material				Wafer Bump	Proce	ess
V	Vafer Fab Site		Wafer Fab	Wafer Fab Materials Wafer Fal			Wafer Fab P	roces	5	
	Part number change									
				D	N D	staile				

## PCN Details

### **Description of Change:**

Texas Instruments is pleased to announce the qualification of ASESH as an alternate assembly and test site for selected MSOP devices listed below. The material set comparing the existing and new site is shown below.

	TIEM	ASESH
Mount Compound	8075531	SID#EY1000063
Mold Compound	4209002	SID#EN2000515
Lead Finish	Matte Sn	NiPdAu

Test coverage, insertions, conditions will remain consistent with current testing and verified with test MQ.

Upon expiry of this PCN TI will combine lead free solutions in a single <u>standard part number</u>, for example; <u>LDC4029MM/NOPB</u> – can ship with both Matte Sn and NiPdAu/Ag.

### Example:

- Customer order for 7500units of LDC4029MM/NOPB with 2500 units SPQ (Standard Pack Quantity per Reel).
- TI can satisfy the above order in one of the following ways.
  - I. 3 Reels of NiPdAu finish.
  - II. 3 Reels of Matte Sn finish
  - III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.
  - IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.

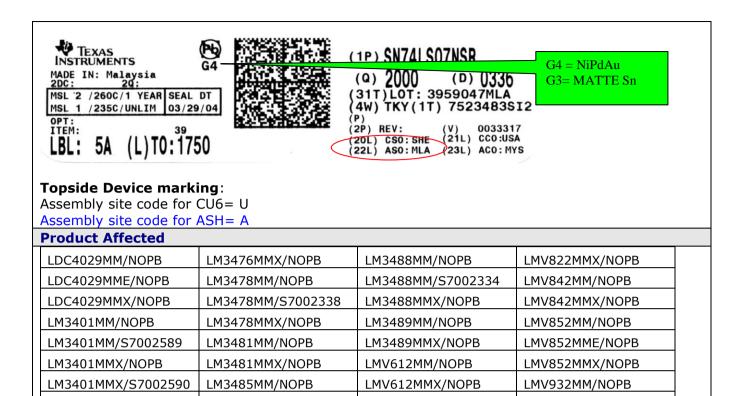
# **Reason for Change:**

Continuity of Supply

Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:					
Assembly Site					
TIEM-AT	Assembly Site Origin (22L)	ASO: CU6			
ASESH	Assembly Site Origin (22L)	ASO: ASH			
Sample product shipping label (not act	tual product label)				



Qualif	ication Data -	<b>Approved August</b>	, 2	013		
This qualification has been	n developed for the	validation of this change	ge.	The qualificati	on data	
validates that the propo	sed change meets	the applicable released	tec	hnical specifica	ations.	
Qua	Vehicle: LM3445	MM/NOPB (MSL 1-20	50C	<b>(3)</b>		
	Package Con	struction Details				
Assembly Site:	ASESH	Mold Compound:	E	N2000515		
# Pins-Designator, Family:	10-DGS, VSSOP	Mount Compound:	E,	Y1000063		
Lead frame (Finish, Base):	NiPdAu, Cu	Bond Wire:	1	1.3 mil Au		
Qualification:			•			
Deliability Teet		Conditions		Sample S	ize/Fail	
Reliability Test		Conditions		Lot#1	Lot#2	
**Biased HAST	130C/85%RH 3	3.3psia (96 Hrs)		75/0	77/0	
**Autoclave 121C	121C, 2 atm (9	121C, 2 atm (96 Hrs) 76/0 77/0				
**T/C -65C/150C	-65C/+150C (5	-65C/+150C (500 Cyc) 75/0 77/0				

LMV822MM/NOPB

LM3485MMX/NOPB

LM3476MM/NOPB

LMV932MMX/NOPB

# Qualification Plan - Estimated Completion: May, 2015

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

# Qualification Device: LM3401MMX/NOPB (MSL 1-260C)

### **Package Construction Details**

Assembly Site:	ASESH	Mold Compound:	EN2000515
# Pins-Designator, Family:	8-DGK, VSSOP	Mount Compound:	EY1000063
Lead Finish:	NiPdAu, Cu	Bond Wire:	1.0 Mil Dia., Au

	<u> </u>	
Oualification:	⊠ Plan	☐ ☐ Test Results
Ouallication.	VIFIGII	I I CSL NCSUILS

Reliability Test	Conditions	Sample Size / Fail					
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3			
High Temp Operating Life	125C (168, 500, 1000 Hours)	77/0	1	1			
Electrical Characterization	Side by side	15/0	1	1			
**High Temp. Storage Bake	150C (500, 1000 Hrs)	77/0	1	1			
**Biased HAST	130C/85%RH (96 Hrs)	77/0	77/0	77/0			
**Autoclave 121C	121C, 2 ATM (96 hrs)	78/0	78/0	78/0			
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0			

Notes: \*\*Tests require preconditioning sequence: MSL1-260C

# Qualification Plan - Estimated Completion: May, 2015

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

# Qualification Device: LM3478MM/NOPB (MSL 1-260C)

### **Package Construction Details**

	. acmage com		
Assembly Site:	ASESH	Mold Compound:	EN2000515
# Pins-Designator, Family:	8-DGK, VSSOP	Mount Compound:	EY1000063
Lead Finish:	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., Au

#### **Qualification: Plan Test Results**

Reliability Test	Conditions	Sample Size / Fail			
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3	
High Temp Operating Life	125C (168, 500, 1000 Hours)	77/0	1	1	
Electrical Characterization	Side by side	30/0	1	1	
**Biased Temp. Humidity	85C/85%RH (168, 500, 1000 Hours)	77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0	
Notes: **Tests require precondi	tioning seguence: MSL1-260C				

Tests require preconditioning sequence: MSL1-2600

# Qualification Plan - Estimated Completion: May, 2015

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

### Qualification Device: LM3481MM/NOPB (MSL 1-260C)

### **Package Construction Details**

Assembly Site:	ASESH	Mold Compound:	EN2000515
# Pins-Designator, Family:	10-DGK, VSSOP	Mount Compound:	EY1000063
Lead Finish:	NiPdAu, Cu	Bond Wire:	1.3 Mil Dia., Au

<b>Oualification:</b>	⊠ Plan	<b>☐</b> Test Results
Ouallication.	/   Fiaii	I I CSL NCSUILS

Reliability Test	Conditions	Sample Size / Fail			
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3	
High Temp Operating Life	125C (168, 500, 1000 Hours)	77/0	1	1	
Electrical Characterization	Side by side	30/0	1	1	
**High Temp. Storage Bake	170C (420 Hours)	77/0	1	1	
**Biased HAST	130C/85%RH (96 Hours)	77/0	77/0	77/0	
**Autoclave 121C	121C, 2 atm (96 Hours)	77/0	77/0	77/0	
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0	

Notes: \*\*Tests require preconditioning sequence: MSL1-260C

# Qualification Plan - Estimated Completion: May, 2015

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

## Qualification Device: LM3485MM/NOPB (MSL 1-260C)

### Package Construction Details

	Assembly Site:	ASESH	Mold Compound:	EN2000515
	# Pins-Designator, Family:	8-DGK, VSSOP	Mount Compound:	EY1000063
	Lead Finish:	NiPdAu, Cu	Bond Wire:	1.0 Mil Dia., Au

#### **Qualification: Plan Test Results**

Reliability Test	Conditions	Sample Size / Fail		
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3
Electrical Characterization	Side by side	30/0	I	
**High Temp. Storage Bake	150C (500, 1000 Hours)	77/0	I	
**Biased Temp. Humidity	85C/85%RH (168, 500, 1000 Hours)	77/0	I	
**Unbiased HAST	130C/85%RH (96 Hours)	77/0	77/0	77/0
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0
Notes: **Tests require preconditioning sequence: MSL1-260C				

# Qualification Plan - Estimated Completion: May, 2015

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

## Qualification Device: LMV822MM/NOPB (MSL 1-260C)

### **Package Construction Details**

Assembly Site:	ASESH	Mold Compound:	EN2000515
# Pins-Designator, Family:	8-DGK, VSSOP	Mount Compound:	EY1000063
Lead Finish:	NiPdAu, Cu	Bond Wire:	1.0 Mil Dia., Au

**Qualification:**  $\square$  **Plan**  $\square$  **Test Results** 

Reliability Test	Conditions	Sample Size / Fail		
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3
Electrical Characterization	Side by side	30/0		
**Biased Temp. Humidity	85C/85%RH (168, 500, 1000 Hours)	77/0		
**Unbiased HAST	130C/85%RH (96 Hours)	77/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0

Notes: \*\*Tests require preconditioning sequence: MSL1-260C

# **Qualification Plan – Estimated Completion: May, 2015**

This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications.

### Qualification Device: LMV842MMX/NOPB (MSL 1-260C)

# Package Construction Details

Fackage Constituction Details			
Assembly Site:	ASESH	Mold Compound:	EN2000515
# Pins-Designator, Family:	8-DGK, VSSOP	Mount Compound:	EY1000063
Lead Finish:	NiPdAu, Cu	Bond Wire:	1.0 Mil Dia., Au

## **Qualification:** $\square$ **Plan** $\square$ **Test Results**

Dolinhility Tost	Conditions	Sample Size / Fail		
Reliability Test	Conditions	Lot 1	Lot 2	Lot 3
Electrical Characterization	Side by side	30/0		
**High Temp. Storage Bake	150C (500, 1000 Hours)	77/0		
**Biased Temp. Humidity	85C/85%RH (168, 500, 1000 Hours)	77/0		
**Unbiased HAST 130C/85%RH (96 Hours)		77/0		
**T/C -65C/150C	-65C/+150C (500 Cyc)	77/0	77/0	77/0
Notes: **Tests require preconditioning sequence: MSL1-260C				

### Qualification Plan - Estimated Completion: May, 2015 This qualification has been specifically developed for the validation of this change. The qualification data validates that the proposed change meets the applicable released technical specifications. Qualification Device: LMV852MMX/NOPB (MSL 1-260C) **Package Construction Details** Assembly Site: **ASESH** Mold Compound: EN2000515 # Pins-Designator, Family: 8-DGK, VSSOP Mount Compound: EY1000063 Lead Frame (Finish/Base): NiPdAu, Cu 1.0 Mil Dia., Au Bond Wire: **Qualification: Plan Test Results** Conditions Reliability Test Sample Size / Fail High Temp Operating Life 125C (125C (168,500,1000 Hours) 77/0 **Electrical Characterization** 30/0 Side by Side \*\*Unbiased HAST 130C/85%RH (96 Hours) 77/0 \*\*T/C -65C/150C -65C/+150C (500 Cyc) 77/0 Notes: \*\*Tests require preconditioning sequence: MSL1-260C

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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